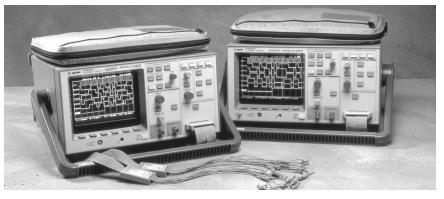
Agilent 54620A/C Logic Analyzers

Product Overview





- 16 Channels
- 500 MSa/s
- 3.5 ns Glitch Capture
- Simple Scope-Like Operation
- Full-Color Display with 54620C

Do you use your scope as your primary tool for troubleshooting digital circuits because you feel that your problems are not complex enough for a logic analyzer? Do you wish that your scope had the power of a logic analyzer without the complexity and cost of one?

If so, these are the logic analyzers for you. With familiar scope-like operation and high speed display, these are logic analyzers that you can simply set on your bench and use like your scope. Because you are a scope user, these are the logic analyzers that you already know how to operate.

The Agilent Technologies 54620A/C is designed to be used with your scope to quickly troubleshoot and debug your mixed signal and digital circuits. The 54620A is the choice for tight budget situations. Its monochrome raster CRT display provides bright crisp displays of our logic waveforms. The 54620C adds a full-color active matrix LCD display. With the addition of color, the logic analyzer's 16-channel display is easy to use. Colors can be used to group or highlight channels.

The Agilent 54620A/C offers:

- · Scope-like control knobs
- Auto scale for one button set-up
- Trigger Input/outputs for use with your scope
- Automatic measurements of frequency, period, duty cycle, width, channel-to-channel delay, hold time, and set-up time
- Cursor measurements and read-out of waveform values in Hex or Binary
- Edge, pattern, and advanced triggering
- Store/recall of 16 front panel setups with channel labels
- Full-color active matrix LCD display (54620C)
- Monochrome raster CRT display (54620A)
- Optional GPIB or RS-232 remote control
- Optional hard copy to GPIB, RS-232, or parallel printers
- Weight 6.8 kg/15 lb.
- 3-Year Warranty

Scope-like operation

The Agilent 54620A/C logic analyzers are designed for the person whose primary analysis tool is the oscilloscope, but often wishes for the additional power of a logic analyzer. This logic analyzer has a control panel that is very much like that of your scope. Simply turn a knob, much like you would on your scope, to make a change in the time per division or reposition a channel in the display. Analyzer set-up is simplified with a powerful Autoscale operation. Autoscale will turn on and display all channels that have activity. The time base will be set to give an optimally scaled display of all active signals.

Flexible triggering

The simplest and most scope-like triggering is provided in the edge triggering mode. The pattern mode extends the triggering to be a pattern of high, low, and "don't care" levels across all 16 of the 54620A's input channels as well as the external trigger input port. This pattern can be qualified



with an edge. For those applications where more triggering power is needed to isolate the event of interest, the Advanced trigger mode is available.

High speed display

An important consideration of a troubleshooting tool is its ability to clearly display changes in the circuit under test. The 54620A/C employs an advanced four processor architecture, giving you a logic analyzer that can display changing waveforms in your system that would be missed by more traditional analyzers. Another benefit of the high speed display system is that the 54620A/C will respond instantly to your front panel control inputs. This eliminates a source of confusion in your troubleshooting process.

See more with color

The display of 16 logic channels can be somewhat confusing. By the use of color, you can group channels that are displaying related information, or specific channels can be highlighted. For example, address lines can be in one color while control lines are displayed in other colors. Alternate palettes allow the display to be customized for most favorable viewing.

Upgrade to meet your changing needs

You can upgrade the Agilent 54620A logic analyzer to produce hard copies to either printer or plotter Or, you can interface it to a computer with either GPIB or RS-232 interfaces.

Using the HP 34810B BenchLink Scope for Windows, you can easily upload the logic analyzer display to your personal computer for preparing a report, creating a presentation, or storing the analyzer's set-up for later use.

20 ns

50 ns

100 ns

200 ns

500 ns

1 µs

> 1 µs

Number of Channels	16 numbered 0–15
Channel Input Cable	54620-61801 with
Onamier input Gable	channels grouped in two
	sets of 8. Instrument
	is compatible with
	0650-61607 cable and
	accessories.
Input R&C	~100kΩ and 8pF
Maximum Input	±40 V
Dynamic Range	±10 V about threshold
Minimum Input	500 mV peak to peak about threshold
Minimum Input	To meet timing accuracy,
Voltage Overdrive	the threshold value must
voitage overunive	be within 20% of the 50%
	value of the input signal
Threshold Setting	Threshold levels can be
-	assigned to the input
	channels in groups of
	8 channels (0-7 and 8-15)
	and external trigger
Threshold Accuracy	± (13% of setting
Preset Threshold Levels	± 100 mV)
rieset inresnoia Levels	TTL—T.5 V CMOS—2.5V
	ECL—1.3 V
Channel to Channel Skew	
	3.0 ns maximum
Horizontal System	
Sweep Speeds	1 s/div to 5 ns/div
	Main & Delayed Sweep Extended to 5s/div with
	Autoglitch disabled
Accuracy	001% of reading
,	Main, Delayed sweeps,
	and verniers
Horizontal Modes	Main, Main and Delayed
	and post acquisition pan
	and zoom
Cursor Accuracy	
Single Channel	± (Sample Period + 0.05%
Single Channel	of reading + 0.2% of
	of reading + 0.2% of screen width)
-	of reading + 0.2% of screen width) ± (Sample Period + Ch
-	of reading + 0.2% of screen width) ± (Sample Period + Ch to Ch skew + 0.01% of
-	of reading + 0.2% of screen width) ± (Sample Period + Ch to Ch skew + 0.01% of reading + 0.2% of screen
Dual Channel	of reading + 0.2% of screen width) ± (Sample Period + Ch to Ch skew + 0.01% of reading + 0.2% of screen width)
Dual Channel Delay Jitter	of reading + 0.2% of screen width) ± (Sample Period + Ch to Ch skew + 0.01% of reading + 0.2% of screen width) 10 ppm
Dual Channel Delay Jitter Delay Range Pretrigger	of reading + 0.2% of screen width) ± (Sample Period + Ch to Ch skew + 0.01% of reading + 0.2% of screen width) 10 ppm (Negative time)
Dual Channel Delay Jitter Delay Range Pretrigger Maximum delay is indep	of reading + 0.2% of screen width) ± (Sample Period + Ch to Ch skew + 0.01% of reading + 0.2% of screen width) 10 ppm
Dual Channel Delay Jitter Delay Range Pretrigger Maximum delay is indep (left, center, right)	of reading + 0.2% of screen width) ± (Sample Period + Ch to Ch skew + 0.01% of reading + 0.2% of screen width) 10 ppm (Negative time)
Dual Channel Delay Jitter Delay Range Pretrigger Maximum delay is indep (left, center, right) Sweep Speed	of reading + 0.2% of screen width) ± (Sample Period + Ch to Ch skew + 0.01% of reading + 0.2% of screen width) 10 ppm (Negative time) endent of time reference
Dual Channel Delay Jitter Delay Range Pretrigger Maximum delay is indep (left, center, right) Sweep Speed (per division)	of reading + 0.2% of screen width) ± (Sample Period + Ch to Ch skew + 0.01% of reading + 0.2% of screen width) 10 ppm (Negative time) endent of time reference Maximum delay divisions
Dual Channel Delay Jitter Delay Range Pretrigger Maximum delay is indep (left, center, right) Sweep Speed (per division) 5 ns 10 ns	of reading + 0.2% of screen width) ± (Sample Period + Ch to Ch skew + 0.01% of reading + 0.2% of screen width) 10 ppm (Negative time) endent of time reference Maximum delay

807

323

161

80.7

64.6

16

16

Post-Trigger Delayed Sweep Operation Post Acquisition Pan & Zoom Operation	(from trigger point to start of sweep) from 5 ns/div to 1 µs/div—8.829 ms From 2 ms/div to 1 s/di—1,048,575 times sampling period, not to exceed 100 s. Delayed can be as fast as 5 ns/div but must be at least 2X main sweep. Acquired waveforms may be panned across the display and/or expanded for enhanced viewing by simply changing time/div or
	delay settings.
Acquisition System	
Maximum Sample Rate Resolution Simultaneous Channels Record Length	Single bit 16 2 k samples at periods of 8 ns and slower (sweep speeds of 1 µs/div to 1 s/div) 8 k samples at sampling periods of 2 ns and 4 ns (sweep speeds of 5 ns/di
Maximum Update Rate	to 500 ns/div), or all sweep speeds when Autoglitch mode is disabled 15 full screens per second independent of the number of channels
Glitch Detect	being displayed. Automatically activated at all sweep speeds where sampling period is slowed to be greater than 4 ns (1 µs/div and slower). Will detect glitches as narrow as 3.5 ns at all activated sweep speeds.
Trigger System	
Sources Auto/Normal Operation	All Channels & External Auto will produce a free running display if the trigger is not found. Normal causes the analyzer to wait indefinitely for a trigger to start acquiring data.
Modes: Edge, Pattern a	nd Advanced
Edge	A single edge can be specified on channels 0–15 and External.

Edge may be rising,

falling, or either.

Analyzer will trigger upon entering a pattern of high, low and don't	Storage Scope	Autostore saves previous sweeps in half bright display and the most	Probe Calibrator	Amplitude 5.0 V, Frequency 9.8 kHz	
care levels on all of the channels and external trigger input. A single	recent sweep full bright display. This allows easy differentiation of		Power Requirements		
edge (rising, falling, or either) can be ANDed and this pattern.		current and historic information.	Voltage selection Line Voltage Range Line Frequency	Automatic 90 to 250 Vac 48 to 445 Hz	
Two unique pattern and edge terms can be combined with operations	Measurement Functions		Max. Power Consumption	100 VA	
to create a very specific trigger event.	Automatic Measurements	The analyzer will perform measurements on the selected input channel(s).	General		
Exited, Duration> time, Duration < time, and Occurs N times. Maximum Occurrence: 2 ²⁰ -1	Single Channel	These measurements are continuously updated. Frequency, Period, + Width, - Width, and	Environmental Characteristics	Meets the requirements of MIL-T-28800D for Type III, Class 3, Style D equipment as described	
Sweep speeds of 5 ns/div to 1 µs/div: 28 ns Sweep speeds of 2 µs/div and slower: 20 ns + 1	Dual Channel	Duty Cycle Channel to Channel delay, Hold-time, and Set-up time.	Ambient Temperature Operating:	below: -10°C to +55°C	
sample period 13 ns + Ch to Ch skew	Cursor Measurements	Two cursors can be positioned on the	Nonoperating: Humidity * Operating:	-51°C to +71°C 95% RH at 40°C for	
5 ns/div to 1 µs/div. At sweep speeds of 2 µds/div and slower = (1 ns + 1 sample period		measurements or read the value of the wave forms at the center. The cursors will track changes in time/div	specification section 75		
At all sweep = 2 sample periods of 16 nss, whichever is greater.		and delay controls. Readout in Time, 1/Time, Hex, and Binary.	Operating: Nonoperating: Vibration Operating	To 4,500 m (15,000 ft) To 15,000 m (50,000 ft) 15 min along each of the three major axes;	
	Set-up Functions	Calanda all andina		0.025-in peak to peak displacement, 10 Hz to 55 Hzs in 1 minute	
\sim 1 m Ω and 12 pF. Compatible with 1007X probes.	Autoscale	channels and places them in the display.	Shock Operating	cycles. Held at 10 min at 55 Hz (4 g at 55 Hz) 30 g. 1/2 sine, T1-ms	
± 40 V peak + 6 V, settable in 50 mV		displayed will be added below those channels already being displayed	Shock operating	duration. 3 shocks/axis along major axis. Total of 18 shock.	
+ 100 mV or 6% of setting whichever is greater 200 mV pp 20 ns		with the lowest numbered channel at the top. Higher numbered channels	EMI Commercial MIL-T-28800D	Meets CISPR 11 Class A Meets the requirements in accordance with	
Output is a rising edge at the trigger point.		down the display. Sweep speed is set to give an optimally scaled		MIL-T-28800 paragraph 3.8.3 table IX, and MIL-STD-461C	
0 to $>/=2.0$ v into 50Ω 0 to $>/=4.8$ V open circuit Data in to trigger out		display of all the active channels. Triggering and are not affected.		CE01: Part 2 CE03: Part 2 CS01: Part 2	
~ 85 ns ± (Sample period + 10 ppm) 2 kHz with the analyzer stopped, 20/sec running.		Requires a signal with > 49 Hz frequency. Undo Autoscale function returns the instrument			
	Save/Recall	Autoscale being activated. 16 front panel set-ups	RE02: Part 2 (limited to 14 kHz to 100 kHz		
54610A: 7" Raster CRT 54620C: 5.8"	Trace Memory	from nonvolatile memory. Two volatile pixel memo-	14 kHz to 1 GHz. This product meets the	requirement of the	
256 Vertical by 500 Horizontal points	Channel I ahels	trace display waveforms.	89/336/EEC. Emissions:	(LO) LINIO DIRECTIVE	
Front panel intensity control Selectable 8 x 10 grid frame, or none	Organier Egnets	identified with a six character label. Labels can be created from a front panel label genera- tor and a library of up to 75 present and user	EN55011/CISPR 1		
	upon entering a pattern of high, low and don't care levels on all of the channels and external trigger input. A single edge (rising, falling, or either) can be ANDed and this pattern. Two unique pattern and edge terms can be combined with operations to create a very specific trigger event. And, Or, Then, Entered, Exited, Duration > time, Duration < time, and Occurs N times. Maximum Occurrence: 2^{20} -1 Sweep speeds of 5 ns/div to 1 μs/div: 28 ns Sweep speeds of 2 μs/div and slower: 20 ns + 1 sample period 13 ns + Ch to Ch skew at sweep speeds of 5 ns/div to 1 μs/div. At sweep speeds of 2 μds/div and slower = $(1 \text{ ns} + 1 \text{ sample period} + Ch to Ch skew + 0.01\%)$ At all sweep = 2 sample period of 16 nss, whichever is greater. $\sim 1 \text{ m}\Omega$ and 12 pF. Compatible with 1007X probes. $\pm 40 \text{ V peak} + 6 \text{ V}$, settable in 50 mV + 100 mV or 6% of setting whichever is greater 200 mV pp 20 ns Output is a rising edge at the trigger point. 0 to >/=2.0 v into 50Ω 0 to >/=2.0 v into 50Ω 0 to >/=2.0 v into 50Ω 1 to >/=2.0 v into 50Ω 2 to >/=4.8 V open circuit Data in to trigger out $\sim 85 \text{ ns}$ $\pm (\text{Sample period} + 10 \text{ ppm})$ 2 kHz with the analyzer stopped, $20/\text{sec}$ running.	upon entering a pattern of high, low and don't care levels on all of the channels and external trigger input. A single edge (rising, falling, or either) can be ANDed and this pattern. Two unique pattern and edge terms can be combined with operations to create a very specific trigger event. And, 0r, Then, Entered, Exited, Duration > time, Duration < time, and Occurs N times. Maximum Occurrence: 2 ²⁰ -1 Sweep speeds of 2 µs/div and slower: 20 ns + 1 sample period + Ch to Ch skew + 0.01%) At all sweep speeds of 2 µds/div and slower = (1 ns + 1 sample period + Ch to Ch skew + 0.01%) At all sweep = 2 sample periods of 16 nss, whichever is greater. — 1 mΩ and 12 pF. Compatible with 1007X probes. ± 40 V peak + 6 V, settable in 50 mV + 100 mV or 6% of setting whichever is greater 200 mV pp 20 ns Output is a rising edge at the trigger point. 0 to >/=2.0 v into 50Ω 0 to >/=4.8 V open circuit Data in to trigger out ~ 85 ns ± (Sample period + 10 ppm) 2 kHz with the analyzer stopped, 20/sec running. Save/Recall 54610A: 7" Raster CRT 54620C: 5.8" active matrix color LCD 256 Vertical by 500 Horizontal points Front panel intensity control Selectable 8 x 10	upon entering a pattern of high, low and don't care levels on all of the channels and external trigger input. A single edge (rising, falling, or either) can be ANDe and this pattern. Two unique pattern and dispartern. Two unique pattern and dege terms can be combined with operations to create a very specific trigger event. And, 0r, Then, Entered, Exited, Durationor time, and Occurs N times. Maximum Occurs N t	upon entering a pattern of high, low and don't care levels on all of the channels and external trigger input. A single odge (rising, falling, or either) can be ANDed and this pattern. sweeps in half bright display. This allows easy differentiation or current and historic information. Power Requirements Voltage selection Line Voltage Range Line Frequency Max. Power Consumption Voltage selection Line Voltage Range Line Frequency Consumption Automatic Inger event. The analyzer will perform measurements on the selected intention. Beauty will perform measurements on the selected intention. Duration - time, Duration - time, Duration - time, and Occurrence; 2"-1 Single Channel Channel to Channel delay, Hold-time, and Set up time. Single Channel Frequency, Period, + Width, - Width, and Set up time. Ambient Temperature Consumption Unid Channel Course M measurements Single Channel 13 ns + Ch to Ch skew 12 pass divide and slower: 20 ns + 1 Cursor Measurements Set up time. Ambient Temperature Consumption Ambient Temperature Consumption Carsor Measurements So to price and solver et 1 ns + 1 sample period + Ch to Ch skew + 0.01%; Channels and places them in the display. Ambient Temperature Consumption Ambient Temperature Channels intime/div Ambient Temperature Operating: Nonoperating: N	

Immunity		
EN50082-1	Code ¹	Notes
IEC, 801-2 (ESD) 4kV CD, SkV AD	1	Α
IEC 801-3 (Rad.) 3V/m	1	Α
IEC 801-4 (EFT) 1kV	1	В

Size	
Height:	172.7 mm (6.8 in)
Width:	322.6 mm (12.7 in)
Depth:	317.5 mm (12.5 in)
Weight:	6.8 Kg (15 lb)
Safety	Self-certified to IEC
	348/HD401, UL 1244,
	CSA-C22 No. 231
	(series M-89)

¹Performance Code

1 PASS—Normal operation, no effect.

2 PASS—Temporary degradation, self-recoverable.
 3 PASS—Temporary degradation, operator intervention required.

4 PASS—Not recoverable, component damage.

²Notes

A TTL logic threshold with all cables disconnected. B TTL logic threshold with GPIB cable connected.

Ordering Information

54620A 16-channel 500 MSa Logic Analyzer

(supplied with 16-channel input cable assembly, User and Service Guide,

as specified by language option) and line cord

54820C Color 16-channel 500 MSa Logic Analyzer

(supplied with 16-channel input cable assembly, User and Service Guide, as specified by language option) and line cord

Manual Language Options (please specify one)

ABA US English ABF French ABO Taiwan Chinese

ABD German ABJ Japanese AB1 Korean

ABE Spanish ABZ Italian

Instrument Options

Opt. 101 Accessory Pouch and Front Panel Cover

Opt. 103 54654A Operator's Training Kit

consists of a training signal board and lab workbook

Opt. 104 1185A Carrying Case

(designed to protect the instrument for shipment or checking as airline baggage)

Opt. 106 HP 34810B BenchLink scope software.

Windows software that interfaces the instrument (with a GPIB or RS-232 module installed) to a PC for storage, analysis, or easy integration of trace images into popular desktop publishing software.

Opt. 001 RS-03 Magnetic shielding (added to the CRT)

(not compatible with the 54620C)

Opt. 1CM Rackmount Kit, seven-inch EIA standard rack mount p/n 5062-7345, compatible with fixed or pivoted slides

Optional Accessories

54650A GPIB Interface Module

54652 RS-232 and Parallel Interface Module

10070A 1.4 m 1X oscilloscope probe

10071A 1.5 m 150 MHz 10X oscilloscope probe

10072A probe adapter kit for 1007X Probes

01650-61607 16-Channel Woven Probe Cable, compatible with

1251-8106 20-pin header

01650-61608 16-Channel Probe Lead Set for use with 01650-61607 cable

E2421A SOIC Clip Adapter Kit

E2422A J lead plastic lead clip carrier test kit

Agilent Technologies' Test and Measurement Support, Services, and Assistance

Agilent Technologies aims to maximize the value you receive, while minimizing your risk and problems. We strive to ensure that you get the test and measurement capabilities you paid for and obtain the support you need. Our extensive support resources and services can help you choose the right Agilent products for your applications and apply them successfully. Every instrument and system we sell has a global warranty. Support is available for at least five years beyond the production life of the product. Two concepts underlie Agilent's overall support policy: "Our Promise" and "Your Advantage."

Our Promise

"Our Promise" means your Agilent test and measurement equipment will meet its advertised performance and functionality. When you are choosing new equipment, we will help you with product information, including realistic performance specifications and practical recommendations from experienced test engineers. When you use Agilent equipment, we can verify that it works properly, help with product operation, and provide basic measurement assistance for the use of specified capabilities, at no extra cost upon request. Many self-help tools are available.

Your Advantage

"Your Advantage" means that Agilent offers a wide range of additional expert test and measurement services, which you can purchase according to your unique technical and business needs. Solve problems efficiently and gain a competitive edge by contracting with us for calibration, extracost upgrades, out-of-warranty repairs, and on-site education and training, as well as design, system integration, project management, and other professional services. Experienced Agilent engineers and technicians worldwide can help you maximize your productivity, optimize the return on investment of your Agilent instruments and systems, and obtain dependable measurement accuracy for the life of those products.

Get assistance with all your test and measurement needs at: www.agilent.com/find/assist

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